

**Search Notes**

Application/Control No.

10/805,890

Examiner

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Applicant(s)/Patent under  
Reexamination

NALLAN ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	58	4/11/2006	BT
216	68	4/11/2006	BT
438	722	4/11/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	4/11/2006	BT